Abstracts

Wide-band 2N-port S-parameter extraction from N-port data

B. Young. "Wide-band 2N-port S-parameter extraction from N-port data." 1998 Transactions on Microwave Theory and Techniques 46.9 (Sep. 1998 [T-MTT]): 1324-1327.

A technique is presented for extracting the full 2N/spl times/2N set of S-parameters for an N-conductor interconnect from five sets of N-port S-parameter measurements on three specially prepared samples. Bandwidth is improved over prior techniques using two samples. Experiments confirm the bandwidth enhancement and illustrate the operational mechanism and accuracy expectations.

❑ Return to main document.